

Search Notes

Application/Control No.

10/630,683

Examiner

PHILIPPE S. DERAQSHANI

Applicant(s)/Patent under
Reexamination

CHEN, YI-CHEN

Art Unit

3754

SEARCHED

Class	Subclass	Date	Examiner
248	447.1	2/1/2006	PD

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
248	447.1	2/1/2006	PD

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR